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PATENTIN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: CHUDoba, T. - 1 PCT
PCT NO. : PCT/DE2003/003556 FILED: OCT. 23, 2003
PRIORITY : GERMAN NO. 102 49 767.2 FILED: OCT. 24, 2002
TITLE : TEST TABLE FOR MEASURING LATERAL FORCES AND
DISPLACEMENTS

INFORMATION DISCLOSURE STATEMENT

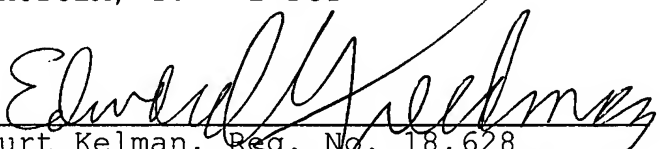
MAILSTOP: PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

Applicants are enclosing Form PTO-1449 disclosing the references cited in the International Search Report, copy enclosed. As it is believed that copies of the references cited in the Search Report were forwarded by the International Office, we are not enclosing copies of these references. Since the instant Information Disclosure Statement is being filed concurrently with the application, no official fee is required in connection with the same.

It is respectfully requested that the foregoing Information Disclosure Statement be incorporated into the official file of the concurrently-filed PCT patent application.

Respectfully submitted,
CHUDoba, T. - 1 PCT

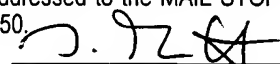

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DATE OF DEPOSIT : April 25, 2005

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10, on the date indicated above, and is addressed to the MAIL STOP: PCT PATENT APPLICATION, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.


Ingrid Mittendorf

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|--|----|--|--|--|-----------------|---------------------------------|-------------------------------|----|
| LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary) | | | | APPLICANT: | | | | |
| | | | | FILING DATE: | | GROUP: | | |
| U.S. PATENT DOCUMENTS | | | | | | | | |
| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE | |
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| | | | | | | | YES | NO |
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| EXAMINER | | | | | DATE CONSIDERED | | | |
| <small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small> | | | | | | | | |